

Quarterly Reliability Monitoring Results

Quarters: Q1/2022 to Q4/2023

Based on structural similarity

Supplier	User Part Number				
Nexperia B.V.	MJD31C				
Name of Laboratory	Part Description				
Nexperia ATGD	Nexperia DHAM Small Signal Bipolar Transistor SOT428, Subcon TFME				
Based on AEC-Q101 Test	Test Conditions	Duration	# Lots	# Quantity	# Rejects
# 1	TEST Pre- and Post-Stress Electrical Test Tamb = 25 °C	N/A	see below	all parts	see below
# 2	PC Preconditioning JESD22-A113 Bake Tamb = 125 °C Soak Tamb = 85 °C, RH = 85% Reflow soldering	24 hours 168 hours 3 cycles	108	4320	0
# 5	HTRB High Temperature Reverse Bias MIL-STD-750-1 M1039 Method A Tj = Tjmax, Vr = 100% of max. datasheet reverse voltage	1000 hours	415	18680	0
# 7	TC Temperature Cycling JESD22-A104 -65 °C to Tjmax, not to exceed 150°C	500 cycles	19	840	0
# 8 or	UHAST Unbiased HAST JESD22-A118 Tamb = 130 °C, RH = 85 %	96 hours	19	840	0
# 8a	AC Autoclave JESD22-A102 Tamb = 121 °C, RH = 100 % Pressure = 205 kPa (29.7 psia)				
# 9	H3TRB High Humidity High Temperature Reverse Bias JESD22-A101 Tamb = 85 °C, RH = 85%, VR = 80 % of rated reverse voltage ^[1]	1000 hours	19	840	0
# 10	IOL Intermittent Operating Life MIL-STD-750 Method 1037 ton = toff, devices powered to insure ΔTj = 100 °C	333 hours	19	840	0
# 20	RSH Resistance to Solder Heat JESD22-A111 260 °C ± 5 °C	10 s	32	960	0
# 21	SD Solderability J-STD-002		8	240	0

[1] The maximum applied voltage is limited by test chamber set up and does not exceed 115V.

Calculation of FIT and MTTF

Test considered for FIT calculation: High Temperature Reverse Bias (HTRB, Test #B1)

Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

Wafer Fab	Technology	Quantity	Rejects	Failure Rate (FIT)	MTTF (hrs)
Nexperia DHAM	Small Signal Bipolar Transistor	18680	0	0,23	4,40E+09

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